

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10051226	LEE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Sheng, Tom V	2629

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
345	87,92,93,103	1/19/2007	TS
349	42,43,54,139,149,152,192		

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Search	1/19/2007	TS

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>